Notice of References Cited 10/705,456 Examiner Art Unit

10/705,456

Reexamination CLARK ET AL.

Examiner

Stephen M. D'Agosta

Art Unit

Page 1 of 1

Applicant(s)/Patent Under

U.S. PATENT DOCUMENTS

Application/Control No.

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	·Name	Classification
	Α	US-2002/0120787 A1	08-2002	Shapiro et al.	709/311
	В	US-6,216,173 B1	04-2001	Jones et al.	715/705
	С	US-2003/0046448 A1	03-2003	Fischer et al.	709/328
	D	US-2003/0177259 A1	09-2003	Wookey et al.	709/237
	Е	US-2001/0010076	07-2001	Wray, Michael	713/151
	F	US-2003/0093495 A1	05-2003	McNulty et al.	709/217
	G	US-2002/0042266 A1	04-2002	Heyward et al.	455/414
	Н	US-6,687,495 B2	02-2004	Bhatia et al.	455/414.1
	ı	US-6,405,106 B1	06-2002	Sheth et al.	701/1
	J	US-2004/0196815 A1	10-2004	Acosta et al.	370/338
	к	US-			
	L	US-			
	М	US-			1170

FOREIGN PATENT DOCUMENTS

*	:	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р	•				
	Q					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	w	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.